4/20/2008

RELIABILITY MONITOR REPORT
FOR

DAL B8 Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS2413	DS8007	DS8113

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 15863 FITS: 7.2

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2007 and 3/31/2008 .

Process Information:

Process Description: DAL B8 Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0713	DS2413	125C, 5.25 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0724	DS8007	125C, 6.0 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0744	DS8113	125C, 6.0 VOLTS	1000 HRS	45	0	
				Total:		**0**	

FAILURE RATE: MTTF (YRS): 15863 FITS: 7.2